

# Calendar of Meetings

## 1987

### **Third International Congress on Applied Mineralogy July 6–10, 1987**

**Orleans, France**

Contact: Secretary ICAM 87, Laboratoire de Mineralogie Appliquée, École Supérieure de l'Énergie et des Matériaux, Domaine Universitaire de la Source, BP 6749, 45067 Orleans Cedex 2-France.

### **36th Annual Denver X-Ray Conference**

**August 3–7, 1987**

**Denver, CO, U.S.A.**

### **Symposium on Neutron Scattering**

**August 8–10, 1987**

**Sydney, Australia**

Contact: Prof. T. M. Sabine, N.S.W. Institute of Technology, PO Box 123, Sydney, Australia.

### **XIXth Congress and General Assembly International Union of Crystallography**

**August 12–20, 1987**

**Perth, Australia**

The scientific program will include invited lectures and contributed papers. Most papers will be in the form of posters. Contact: Crystallography Centre, University of Western Australia, Perth 6009, Australia.

### **Satellite Meeting on X-Ray Powder Diffractometry Thursday August 20–Saturday August 22, 1987**

**Freemantle, Western Australia**

#### **Scope of Meeting**

The meeting will comprise a symposium on automated data acquisition and analytical procedures in industry with special reference to:

- (i) data acquisition
- (ii) automated profile processing and
- (iii) quantitative studies of materials, including Rietveld methods.

Contact: Dr. Brian O'Connor, School of Physics and Geophysics, Western Australian Institute of Technology, Kent Street, Bentley, W.A. 6102, Australia. Please mark envelope "Attention SMXPD" Telephone: (619) 350-7192 Telex AA92983.

### **Symposium on Accuracy in Structure Factor Measurements**

**August 23–26, 1987**

**Melbourne, Australia**

Contact: Dr. S. W. Wilkins, CSIRO Division of Chemical Physics, PO Box 160, Clayton 3168, Australia.

### **Solid State Properties of Minerals**

**August 24–26, 1987**

**Sydney, Australia**

Contact: D. Haneman, Univ. of New South Wales, Australia.

### **Conference on Structure and Reactivity of Solids and Solid Surfaces**

**August 24–29, 1987**

**Sydney, Australia**

Contact: Dr. R. St. C. Smart, School of Science, Griffith University, Nathan 4111, Australia.

### **High Pressure Geosciences and Materials Synthesis**

**August 25–27, 1987**

**Potsdam, German Democratic Republic**

Contact: Prof. H. Vollstadt, Acad. der Wissenschaften der DDR, Zentralinstitut für Physik der Erde, Telegrafenberg, Potsdam 1500 DDR.

### **EMAG '87**

**September 6–11, 1987**

**Manchester, U.K.**

Emphasis will be on high spatial resolution analytical electron microscopy. Contact: The Meetings Officer, The Institute of Physics, 47 Belgrave Square, London SW1X 8QX, U.K.

### **International Conference on Advanced Methods in X-Ray and Neutron Structure Analysis of Materials**

**October 5–9, 1987**

**Karlovy Vary, Czechoslovakia**

The main topics of the conference will be the utilization of advanced methods in the study of phase analysis, thin films and surface layers, and crystal structure solution of modulated and polytype structures. The plenary sessions will review the state of the art in these fields. Contributed papers and posters will present original work. Contact: SKODA Plzen, Development and Specialization Department, Mrs. I. Vostrakova, 31600 Plzen, Czechoslovakia.

### **ECASIA '87**

#### **European Conference on Applications of Surface and Interface Analysis**

**October 19–23, 1987**

**Fellbach near Stuttgart, F. R. G.**

Contributions on all aspects of surface science. Contact: Mrs. U. Nagorny, MPI für Metallforschung, Seestr. 92, D-7000 Stuttgart 1, F. R. G.

### **Geological Society of America**

**October 26–29, 1987**

**Phoenix, Arizona, U.S.A.**

Contact: Jean Kinney, GSA, Box 9140, Boulder, Colorado, U.S.A.

**39th Southeastern Regional Meeting of the  
American Chemical Society  
November 4-6, 1987  
Orlando, FL, USA**

The program includes a workshop on X-Ray Powder Diffractometry. Contact: Mike Hampton, Chemistry Department, University of Central Florida, Orlando, FL 32806, U.S.A.

# 1989

**28th International Geological Congress  
July 9-19, 1989  
Washington, DC, U.S.A.**

# 1988

**EUREM '88  
9th European Congress on Electron Microscopy  
September 4-9, 1988  
York, England**

All aspects of electron microscopy; special emphasis on new instrumentation. Contact: Congress Secretariat, The Royal Microscopical Society, 37/38 St. Clements, Oxford OX4 1AJ, England.

## JCPDS-ICDD Subcommittee Activities

### Target Systems for Technical Committee Activities

The term "Target Systems" in the name of this subcommittee refers to systems of phases that are targeted to eventually be added to the JCPDS database of reference patterns (currently over 46,000). The purpose of the subcommittee is to enhance the JCPDS file by adding diffraction patterns of common and important phases that are not currently in the file.

To accomplish this, several steps are necessary. First, common and important phases that are missing must be identified. Important to whom? Important to users of the JCPDS file: the people actually generating powder diffraction patterns who need reference patterns to help make identifications. To do this, several Task Groups have been established to contact diffraction laboratories to find out which phases would have helped in the identification of samples in their laboratories, if they had been in the JCPDS file. The second step is to actually obtain samples of these missing phases. We may get them from the laboratories which suggested them in the first place, or we may have to have them specially prepared (single phase) by other laboratories if the phases were originally in mixtures. The third step is to obtain X-ray Diffraction patterns of these single phase samples. Again, these might come from the original laboratories, or from the laboratories that prepared the single phases, or yet other laboratories may actually generate, index, and refine to an acceptable diffraction pat-

tern. Lastly, the final pattern must go through the usual editorial process before it can be added to the JCPDS file. Laboratories that prepared and refined the patterns will be given credit in the reference portion of the card image in the file.

X-ray diffraction laboratories are invited to help this subcommittee with any of the steps mentioned above. Contact the chairman of a Task Group, or, if you would like to see another Task Group formed, such as "Pesticides," contact me.

### Target System Task Groups

#### *Cements and Hydration Products*

Although the phase assemblage that comprises cement clinker is well known, variations in the raw feed stock from source to source result in differing degrees of solid solution, which makes automated identification difficult at best. The objective of this Task Group is to establish the shortcomings of the JCPDS database for commercial cementitious phases and their hydration products. Both Portland-based and aluminate-based cement systems will be considered. Further, the Task Group will attempt to identify individuals and organizations who are actively producing appropriate cementitious phases with the objective of securing samples.

Barry E. Scheetz  
Materials Research Lab  
The Pennsylvania State University  
University Park, PA 16802  
814-865-3539